

# Is Now Part of



# ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <a href="https://www.onsemi.com">www.onsemi.com</a>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, emplo



April 2009

# FDS4435BZ

# P-Channel PowerTrench<sup>®</sup> MOSFET -30V, -8.8A, 20m $\Omega$

### **Features**

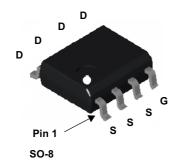
- Max  $r_{DS(on)}$  = 20m $\Omega$  at  $V_{GS}$  = -10V,  $I_D$  = -8.8A
- Max  $r_{DS(on)}$  = 35m $\Omega$  at  $V_{GS}$  = -4.5V,  $I_D$  = -6.7A
- Extended V<sub>GSS</sub> range (-25V) for battery applications
- HBM ESD protection level of ±3.8KV typical (note 3)
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- Termination is Lead-free and RoHS compliant

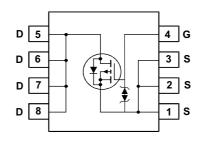


### **General Description**

This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.





# **MOSFET Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-30	V
$V_{GS}$	Gate to Source Voltage			±25	V
	Drain Current -Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-8.8	Α
'D	-Pulsed			-50	<b>7</b> A
В	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	2.5	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1b)	1.0	VV
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 4)	24	mJ
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

# **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS4435BZ	FDS4435BZ	SO-8	13"	12mm	2500units

# **Electrical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25°C		-21		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24V, V_{GS} = 0V$			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±10	μΑ

# On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-2.1	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = -250μA, referenced to 25°C		6		mV/°C
		$V_{GS} = -10V, I_D = -8.8A$		16	20	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = -4.5V, I_D = -6.7A$		26	35	mΩ
, ,		$V_{GS} = -10V$ , $I_D = -8.8A$ , $T_J = 125$ °C		22	28	Ī
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5V, I_{D} = -8.8A$		24		S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 45V V - 0V	1385	1845	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> = 0V, If = 1MHz	275	365	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11VII 12	230	345	pF
$R_g$	Gate Resistance	f = 1MHz	4.5		Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		10	20	ns
t <sub>r</sub>	Rise Time	$V_{DD}$ = -15V, $I_{D}$ = -8.8A, $V_{GS}$ = -10V, $R_{GEN}$ = 6 $\Omega$	6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10V, K <sub>GEN</sub> = 652	30	48	ns
t <sub>f</sub>	Fall Time		12	22	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0V to -10V	28	40	nC
$Q_q$	Total Gate Charge	$V_{GS} = 0V \text{ to } -5V$ $V_{DD} = -15V,$ $I_{D} = -8.8A$	16	23	nC
$Q_{gs}$	Gate to Source Charge	I <sub>D</sub> = -0.0A	5.2		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		7.4		nC

# **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = -8.8A (Note 2)		-0.9	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = -8.8A. di/dt = 100A/us		29	44	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1 <sub>F</sub> = -0.6A, α//αι = 100A/μs		23	35	nC

NOTES:

<sup>1.</sup> R<sub>0,1A</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,1C</sub> is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
- 4. Starting  $T_J$  = 25°C, L = 1mH,  $I_{\mbox{\scriptsize AS}}$  = -7A,  $V_{\mbox{\scriptsize DD}}$  = -30V,  $V_{\mbox{\scriptsize GS}}$  = -10V

# **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

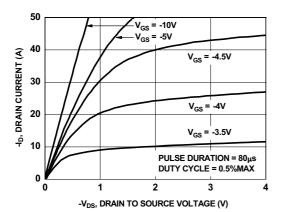


Figure 1. On-Region Characteristics

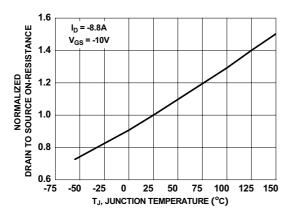


Figure 3. Normalized On-Resistance vs Junction Temperature

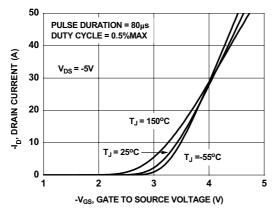


Figure 5. Transfer Characteristics

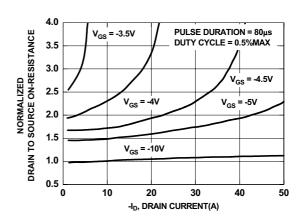


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

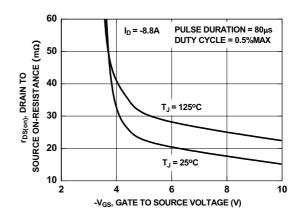


Figure 4. On-Resistance vs Gate to Source Voltage

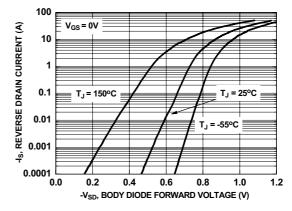


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

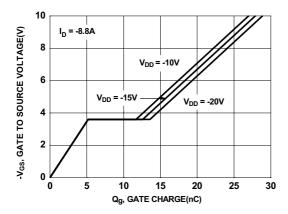


Figure 7. Gate Charge Characteristics

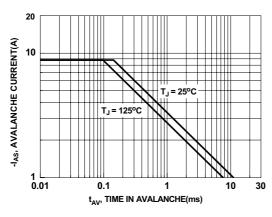


Figure 9. Unclamped Inductive Switching Capability

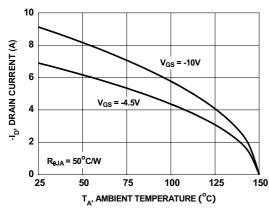


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

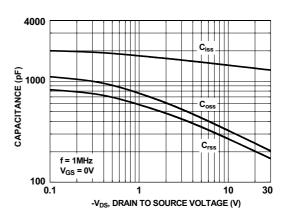


Figure 8. Capacitance vs Drain to Source Voltage

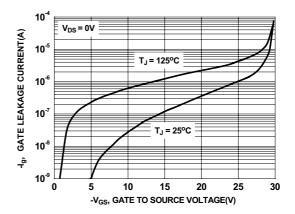


Figure 10. Gate Leakage Current vs Gate to Source Voltage

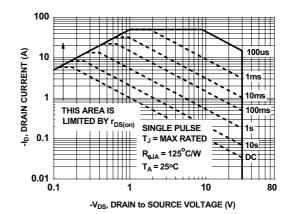


Figure 12. Forward Bias Safe Operating Area

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

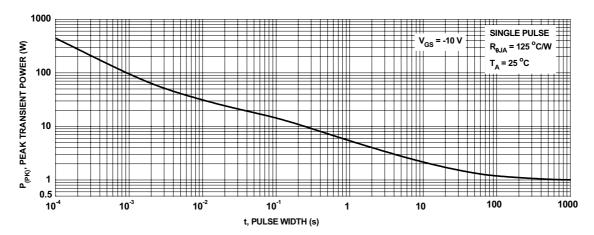


Figure 13. Single Pulse Maximum Power Dissipation

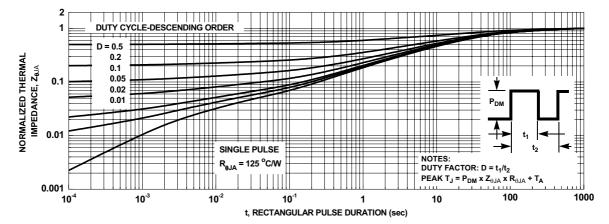


Figure 14. Transient Thermal Response Curve



The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Auto-SPM™ Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™

CTL™ Current Transfer Logic™ FcoSPARK<sup>®</sup> EfficentMax™ EZSWITCH™ \*

Fairchild®

Fairchild Semiconductor® FACT Quiet Series™

FACT<sup>®</sup> FAST® FastvCore™ FETBench™ FlashWriter® \* F-PFS™ FRFET®

Global Power Resource<sup>SM</sup>

Green FPS™ Green FPS™ e-Series™ Gmax™

GTO™ IntelliMAX™ ISOPLANAR™ MegaBuck™ MIČROCOUPLER™ MicroFET™

MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™ Programmable Active Droop™

QSTM Quiet Series™ RapidConfigure™

QFET®

Saving our world, 1mW /W /kW at a time™

SmartMax™ SMART START™ SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™

Sync-Lock™ SYSTEM ®\* The Power Franchise®

puwer franchise TinyBoost™ TinyBuck™ TinyLogic® TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TriFault Detect™ TRUECURRENT™\* μSerDes™

**UHC®** Ultra FRFET™ UniFET™ VCX<sup>TM</sup> VisualMax™ XS™

\*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

**LIFE SUPPORT POLICY**FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their

parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information Formative / In Design Datasheet contains the may change in any may		Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
		Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 140

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and h

# **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative